

**Prof. Laurent HOUSSIAU**  
**Region: Europe**

Civil Engineer in Material Sciences (University of Louvain, 1991), PhD in Applied Sciences (University of Louvain, Bertrand's group, 1996), Post-Doc in the University of Houston (Rabalais's group, 1997-1999), Professor in the University of Namur, Belgium, since 2000.

Author of 60 publications in the field of surface and interface analysis with ion beams. Expert in Low Energy Ion scattering (LEIS) during his PhD and post-doc, then specialized in ToF-SIMS since 1999. His main focus is on very low energy ion depth profiling on both organics and inorganics. Research on MCs clusters, Cs/Xe cosputtering and, more recently, molecular depth profiling with low energy reactive ions (Cs<sup>+</sup> and O<sub>2</sub><sup>+</sup>). He has also recently started fundamental studies on low pressure RF-plasma polymerization.

**International SIMS network:**

Research projects with ION-TOF (D), U. Münster (D), SAM (Luxemburg), Oxford (UK), U. Louvain (B), IMEC (B), U. Antwerp (B), Cameca (F), TU Vienna (A), EMPA (CH), NIST (USA), U. Washington (USA)...

**Leadership:**

- Head of the Physics Department in the University of Namur (100 people)
- 4 PhD students, 3 postdocs, as of September 2009
- Research and financial responsibility for 8 projects funded by Europe or Belgian government (3 running in 2009).

Regular referee for SIA, RCMS, IJMS, Langmuir, Surf. Sci, Appl. Surf. Sci...

Participated in all SIMS conferences since 1999 (SIMS 12-17), four SIMS Europe (2002-2008) and one US SIMS Workshop (2008).